



# **MachXO4 Hardware Checklist**

## **Technical Note**

FPGA-TN-02411-1.0

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## Abbreviations in This Document

A list of abbreviations used in this document.

Abbreviation	Definition
FB	Ferrite Bead
FPGA	Field Programmable Gate Array
GPLL	Global Phase-Locked Loop
GPIO	General Purpose Input/Output
HCSL	High-Speed Current Steering Logic
IBIS	I/O Buffer Information Specification
I2C	Inter-Integrated Circuit
JTAG	Joint Test Action Group
LVDS	Low Voltage Differential Signalling
MSPI	Master Serial Peripheral Interface
PCB	Printed Circuit Board
PCI	Peripheral Component Interconnect
PLL	Phase-Locked Loop
POR	Power-On Reset
SPI	Serial Peripheral Interface
SRAM	Static Random Access Memory
SSPI	Slave Serial Peripheral Interface
SSO	Simultaneous Switching Output
WISHBONE	Open Source Bus Interface

# 1. Introduction

When designing complex hardware using the MachXO4™ device, designers must pay special attention to critical hardware configuration requirements. This technical note outlines the critical hardware requirements related to the MachXO4 device. This document does not provide detailed step-by-step instructions but offers a high-level summary checklist to assist in the design process.

Hardware checklists are developed after evaluation boards and incorporate optimized designs that improve upon the circuitry of the evaluation boards. If you copy circuits from evaluation boards, ensure to optimize your designs according to the hardware checklists.

The MachXO4 devices comes in high-performance version, HC and HE. The high-performance devices are available in two speed grades, –5 and –6, with –6 being faster. HC devices have an internal linear voltage regulator supporting external VCC supply voltages of 3.3 V or 2.5 V, while HE devices accept only 1.2 V as the external VCC supply voltage. All HC and HE parts are functionally and pin-compatible.

This technical note assumes familiarity with the MachXO4 device features as described in the [MachXO4 Family Data Sheet \(FPGA-DS-02125\)](#).

The critical hardware areas covered in this technical note are:

- Power supplies, including MachXO4 supply rails and their connections to the PCB and associated system.
- Configuration, including mode selection connection for proper power-up.
- Device I/O interfaces and critical signals.

**Important:** Refer to the following documents for detailed recommendations:

- [Power and Thermal Estimation and Management for MachXO4 Devices \(FPGA-TN-02409\)](#)
- [MachXO4 sysIO User Guide \(FPGA-TN-02398\)](#)
- [Implementing High-Speed Interfaces with MachXO4 Devices \(FPGA-TN-02410\)](#)
- [MachXO4 Programming and Configuration Usage Guide \(FPGA-TN-02393\)](#)
- [Using Hardened Control Functions in MachXO4 Devices \(FPGA-TN-02403\)](#)

## 2. Power Supply

The  $V_{CC}$  and  $V_{CCIO0}$  power supplies determine the MachXO4 internal power-good condition. These supplies must be at a valid and stable level before the device can become operational. In addition, five supplies ( $V_{CCIO1}$  to  $V_{CCIO5}$ ) power the remaining I/O banks. Table 2.1 shows the power supplies and their corresponding voltage levels. Refer to the [MachXO4 Family Data Sheet \(FPGA-DS-02125\)](#) for more information on the Power-On-Reset (POR),  $V_{CC}$ , and  $V_{CCIOx}$  voltage levels.

**Table 2.1. Power Supply Description and Voltage Levels**

Supply	Voltage (Nominal Value)	Description
$V_{CC}$	1.2 V	Core power supply for 1.2 V devices (HE)
	2.5 V/3.3 V	Core power supply for 2.5 V/3.3 V devices (HC)
$V_{CCIOx}$	1.2 V to 3.3 V	Power supply pins for I/O Bank x. There are up to five I/O banks.

### 2.1. Power Noise

The power rail voltages of the FPGA allow for a worst-case normal operating tolerance of  $\pm 5\%$  of these voltages. The 5% tolerance includes any noise.

### 2.2. Power Source

$V_{CC}$  and  $V_{CCIOx}$  power rails of the same voltage should originate from the same voltage regulator to ensure proper power sequencing.

It is recommended that the designed voltage regulators are accurate to within 3% of the optimum voltage to allow power noise design margin.

When calculating the total voltage regulator tolerance, include:

- Regulator voltage reference tolerance.
- Regulator line tolerance.
- Regulator load tolerance.
- Tolerances of any resistors connected to the regulator's feedback pin, which sets the regulator's output voltage.
- Expected voltage drops due to the power filtering ferrite bead's ESR  $\times$  expected current draw.
- Expected voltage drops due to the current measuring resistor's resistance  $\times$  expected current draw.

With a 3% tolerance allocated to the voltage source, the design has a remaining 2% tolerance for noise and layout related issues. The 1.2 V rail is particularly sensitive to noise, as every 12 mV represents 1% of the rail voltage. For banks supporting sensitive differential signals (LVDS, MIPI, and the like) target for the bank's  $V_{CCIOx}$  less than 1.0% peak noise to minimize jitter.



## 3. Power Supply Filtering

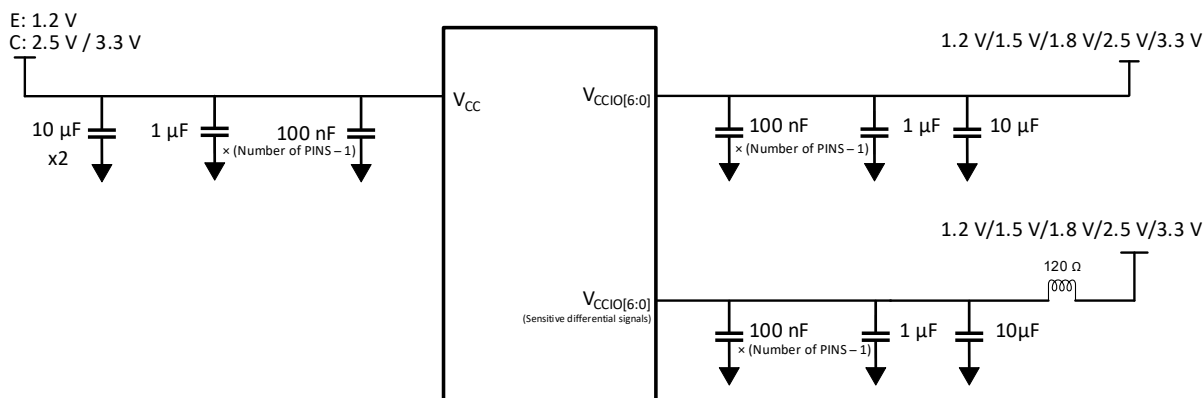
Providing a quiet, filtered supply is important for all rails, and critical for the analog rails. Supplies should be decoupled using adequate power filters. Bypass capacitors must be located close to the device package pins, with very short traces to minimize inductance.

For optimal performance, assign pins carefully to keep noisy I/O pins away from sensitive functional pins. PCB-related crosstalk with sensitive blocks is often caused by FPGA outputs located near sensitive power supplies. These supplies require careful board layout to ensure immunity to switching noise generated by FPGA outputs. Guidelines are provided for building quiet-filtered analog supplies; however, robust PCB layout is required to prevent noise infiltration.

### 3.1. Recommended Power Filtering Groups and Components

**Table 3.1. Recommended Power Filtering Groups and Components**

Power Input	Recommended Filter	Notes
$V_{CC}$	$10\ \mu\text{F} \times 2 + 1.0\ \mu\text{F} + 100\ \text{nF} \times (\# \text{ rail power pins} - 1)$	Core and clock logic. For 1.2 V devices (HE) For 2.5 V/3.3 V devices (HC)
$V_{CCIO[6:0]}$	Each $V_{CCIOx}$ : $10\ \mu\text{F} + 1.0\ \mu\text{F} + 100\ \text{nF} \times (\# \text{ rail power pins} - 1)$  For banks supporting sensitive differential signals (LVDS, MIPI, and the like) add a series ferrite bead: FB $120\ \Omega + 10\ \mu\text{F} + 1.0\ \mu\text{F} + 100\ \text{nF} \times (\# \text{ rail power pins} - 1)$	Bank I/O. For unused banks, a single $1.0\ \mu\text{F}$ is sufficient. For banks with many outputs or large capacitive loading, replace the $10\ \mu\text{F}$ with a $22\ \mu\text{F}$ (or use two $10\ \mu\text{F}$ ). 1.2 V, 1.5 V, 1.8 V, 2.5 V, 3.3 V



**Figure 3.1. Recommended Power Filter Group**

### 3.2. Ground Pins

All ground pins must be connected to the board's ground plane.

### 3.3. Unused GPIO Pins

Leave all unused GPIO pins open.

(It is recommended to connect a few unused GPIOs to test points to facilitate debugging and bring-up rework.)

### 3.4. Unused Banks ( $V_{CCIOx}$ )

Connect unused  $V_{CCIOx}$  pins to a power rail; do not leave them unconnected.

It is recommended to bypass unused banks' rail pins with a single 1.0uF or 100 nF capacitor.

### 3.5. Clock Oscillator Supply Filtering

When providing an external reference clock to the FPGA — such as from a single-ended or differential clock oscillator, ensure proper power supply isolation and decoupling of the oscillator.

When specifying components, choose good-quality ceramic capacitors in small packages, and place them as close as possible to the clock oscillator supply pins.

## 4. Power

### 4.1. Power Sequencing

$V_{CC}$  and  $V_{CCIOX}$  power rails of the same voltage must be supplied by the same voltage regulator to ensure proper power sequencing.

### 4.2. Power Estimation

Once the MachXO4 device density, package, and logic implementation are determined, power estimation can be performed using the Power Calculator tool, provided as part of the Lattice Radiant™ design software. During power estimation, keep the following two goals in mind:

- Power supply budgeting must be based on the maximum power-up in-rush current, configuration current, and maximum DC and AC current under the system's environmental conditions.
- The ability of the system environment and MachXO4 device packaging to maintain the specified maximum operating junction temperature.

By evaluating these two criteria, system design planning can incorporate the MachXO4 device power requirements early in the design phase.

These considerations are detailed in [Power and Thermal Estimation and Management for MachXO4 Devices \(FPGA-TN-02409\)](#).

## 5. Component Selection

### 5.1. Ferrite Bead Selection

- Most designs work well with ferrite beads rated between 120  $\Omega$  at 100 MHz and 240  $\Omega$  at 100 MHz.
- Ferrite bead-induced noise voltage from  $ESR \times CURRENT$  should be less than 1% of the rail voltage.
- Use ferrite beads with ESR between 0.01  $\Omega$  and 0.10  $\Omega$ , depending on current load.
- Small-package ferrite beads have higher ESR than large-package beads of the same impedance.
- High-impedance ferrite beads have higher ESR than low-impedance beads of the same package size.

### 5.2. Capacitor Selection

When specifying components, choose good-quality ceramic capacitors in small packages, and place them as close to the supply pins as possible. *Good quality* capacitors for bypassing generally meet the following requirements:

#### 5.2.1. Capacitor Dielectric

Use dielectrics such as X5R, X7R, which have good capacitance tolerance ( $\leq \pm 20\%$ ) over temperature range. Avoid Y5V, Z5U, and other dielectrics with poor capacitance control.

#### 5.2.2. Voltage Rating

A capacitor working capacitance decreases nonlinearly with increasing voltage bias. To maintain capacitance, the capacitor's voltage rating should be at least 80% higher than the maximum rail voltage. For example, bypass capacitors on a 3.3 V rail should have a minimum rating of 6.3 V.

#### 5.2.3. Size

Smaller-body capacitors have lower inductance, operate at higher frequencies, and improve board layout. For a given voltage rating, smaller-body capacitors tend to cost more than larger ones. Balancing market pricing and size-related inductance, the following capacitor sizes are recommended:

**Table 5.1. Recommended Capacitor Sizes**

Capacitance	Size Preferred	Size Next Best
0.1 $\mu F$ , 1.0 $\mu F$	0201	0402
2.2 $\mu F$	0402	0201
4.7 $\mu F$	0402	0603
10 $\mu F$	0402	0603
22 $\mu F$	0805	0603

#### 5.2.4. Mounting Location

Place the 0.1  $\mu F$  and 1.0  $\mu F$  capacitors close to the MachXO4 associated power rail pins. Selecting 0201 package size allows these capacitors to fit on the opposite side of the PCB from the MachXO4 device, between ball pad via holes.

## 6. Configuration Considerations

The MachXO4 devices contain two types of memory: SRAM and Flash. SRAM is a volatile memory and contains the active configuration. Flash is nonvolatile memory that provides on-chip storage for the SRAM configuration data and user data.

The MachXO4 device includes multiple programming and configuration interfaces:

- 1149.1 JTAG
- Self-download
- Target SPI (SSPI)
- Controller SPI (MSPI)
- Dual Boot
- I2C
- WISHBONE bus

For ease of prototype debugging, it is recommended that every PCB provide easy access to the programming and configuration pins.

The configuration logic arbitrates access among the interfaces in the following priority. When higher-priority ports are enabled, Flash access by lower-priority ports is blocked.

- JTAG Port
- Target SPI (SSPI) Port (SN low activates the SPI port)
- I2C Primary Port

**Note:** Erased devices have all programming and configuration ports enabled by default. When the device is erased, ensure that SN and PROGRAMN are not driven low.

For a detailed description of the programming and configuration interfaces, refer to the [MachXO4 Programming and Configuration User Guide \(FPGA-TN-02393\)](#).

External resistors are required when configuration signals are used to handshake with other devices. Pull-up and pull-down resistor (4.7 k $\Omega$ ) recommendations for various configuration pins are listed below.

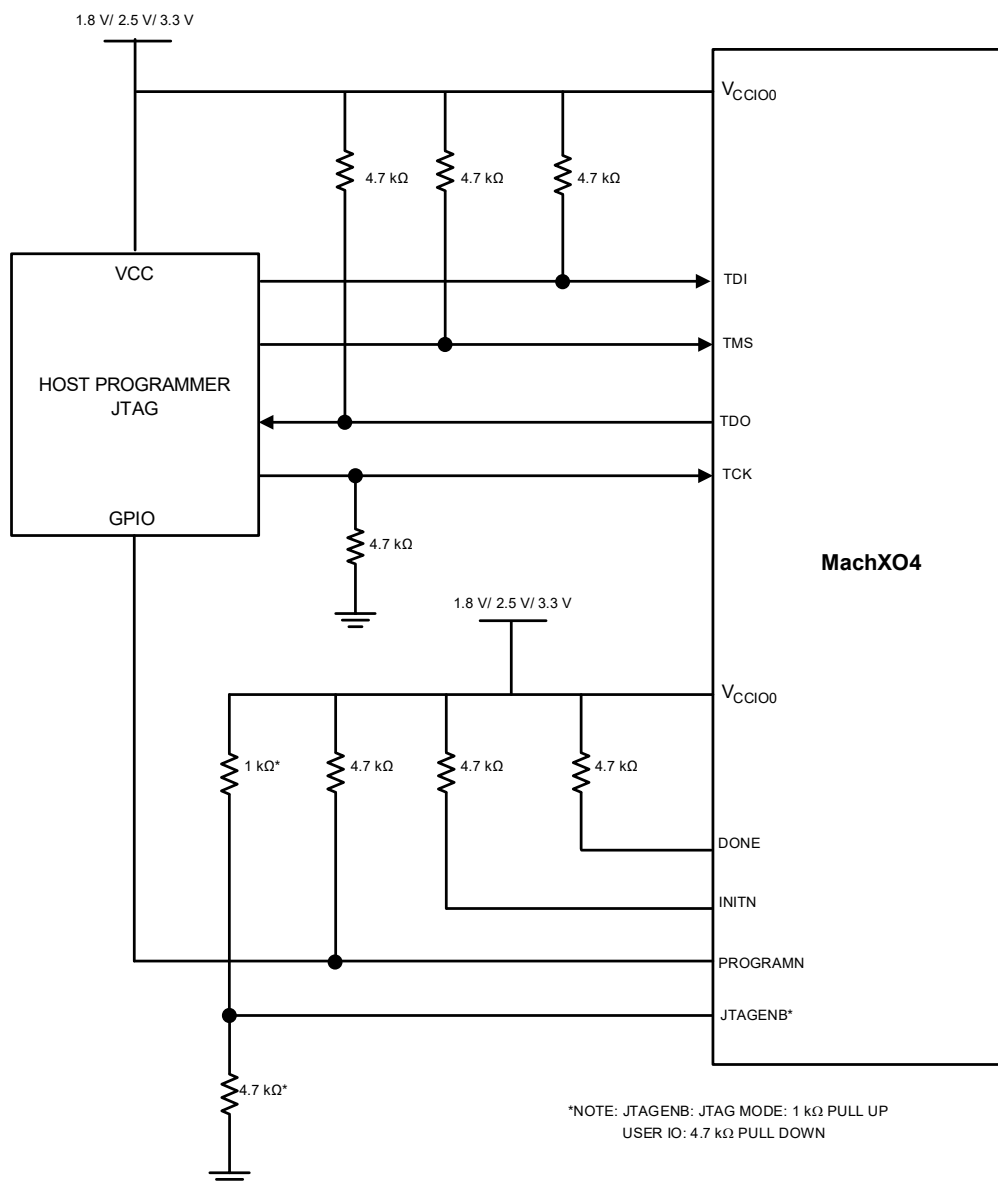
**Table 6.1. Default States of the sysCONFIG Pins<sup>1</sup>**

Pin Name	Pin Function (Configuration Mode)	Pin Direction (8-Bit Size)	Data In Bits that Get Masked (9-Bit Size)
PROGRAMN	PROGRAMN	Input with weak pull-up; external pull-up to V <sub>CCIO0</sub> .	PROGRAMN
INITN	I/O	I/O with weak pull-up; external pull-up to V <sub>CCIO0</sub> .	User-defined I/O
DONE	I/O	I/O with weak pull-up, external pull-up to V <sub>CCIO0</sub> .	User-defined I/O
MCLK/CCLK <sup>2</sup>	SSPI	Input with weak pull-up. MCLK function requires a 510 $\Omega$ to 1 k $\Omega$ pull-up to V <sub>CCIO2</sub> ; place the series resistor near the Tx side.	User-defined I/O
SN	SSPI	Input with weak pull-up; external pull-up to V <sub>CCIO2</sub> .	User-defined I/O
SI/SPISI	SSPI	Input	User-defined I/O
SO/SOSPI	SSPI	Output	User-defined I/O
CSSPIN	I/O	I/O with weak pull-up; external pullup to V <sub>CCIO2</sub> .	User-defined I/O
SCL	I2C	Bidirectional open-drain; external pull-up; noise filter (200 $\Omega$ series/ 100 pF to GND).	User-defined I/O
SDA	I2C	Bi-Directional open drain; external pull-up; noise filter (100 $\Omega$ series/ 100 pF to GND).	User-defined I/O
TDI	TDI	Input with weak pull-up.	TDI
TDO	TDO	Output with weak pull-up.	TDO
TCK	TCK	Input. Recommended 4.7 k $\Omega$ pull-down resistor.	TCK

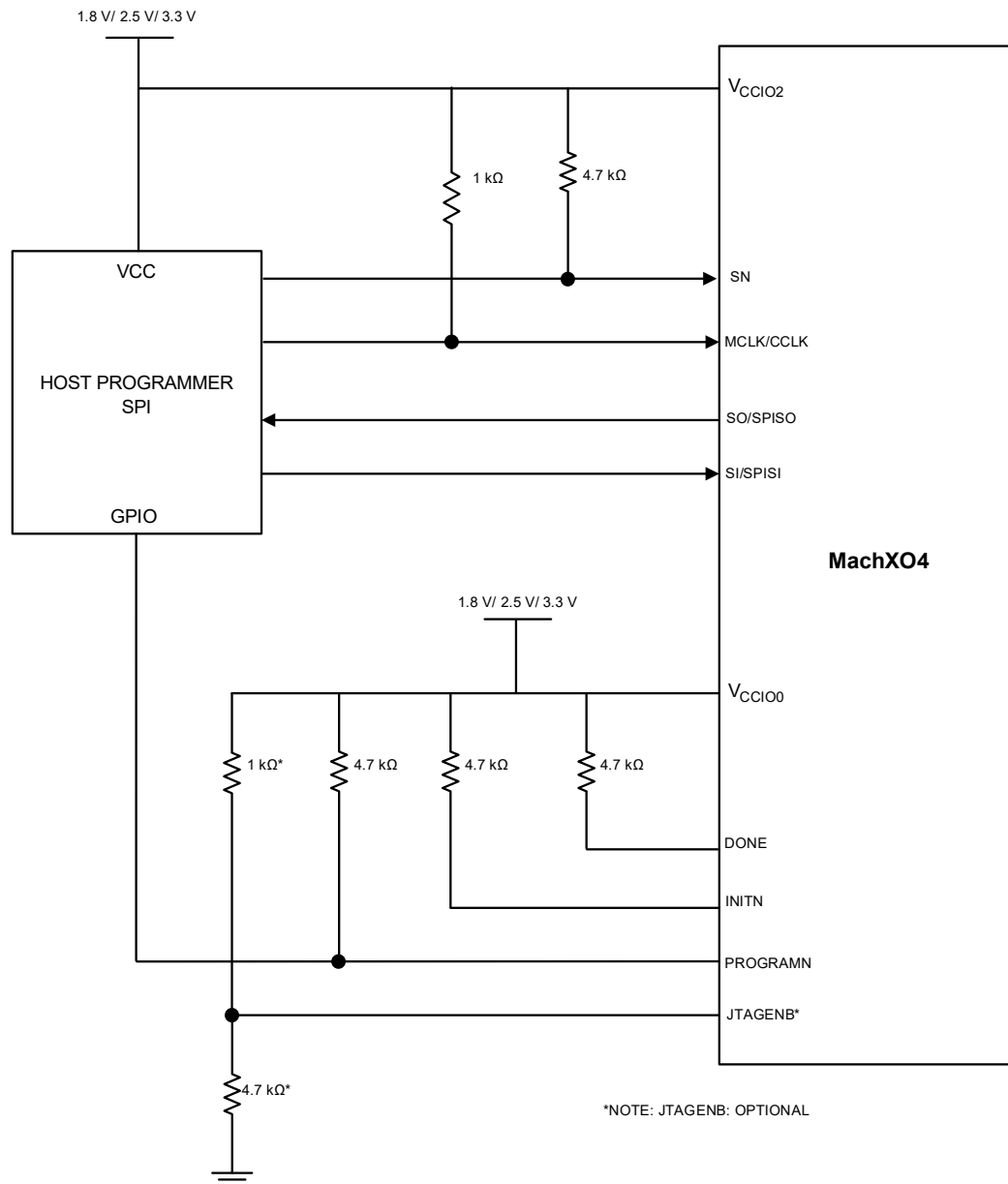
Pin Name	Pin Function (Configuration Mode)	Pin Direction (8-Bit Size)	Data In Bits that Get Masked (9-Bit Size)
TMS	TMS	Input with weak pull-up.	TMS
JTAGENB	I/O	Input with weak pull-down.	I/O

**Note:**

1. Leave the unused configuration ports open.
2. The series resistor value depends on the PCB design. The range is from 22  $\Omega$  to 39  $\Omega$ .



**Figure 6.1. Typical Connections for Programming SRAM or Internal Flash via JTAG**



**Figure 6.2. Typical Connections for Programming SRAM or Internal Flash via SSPI**

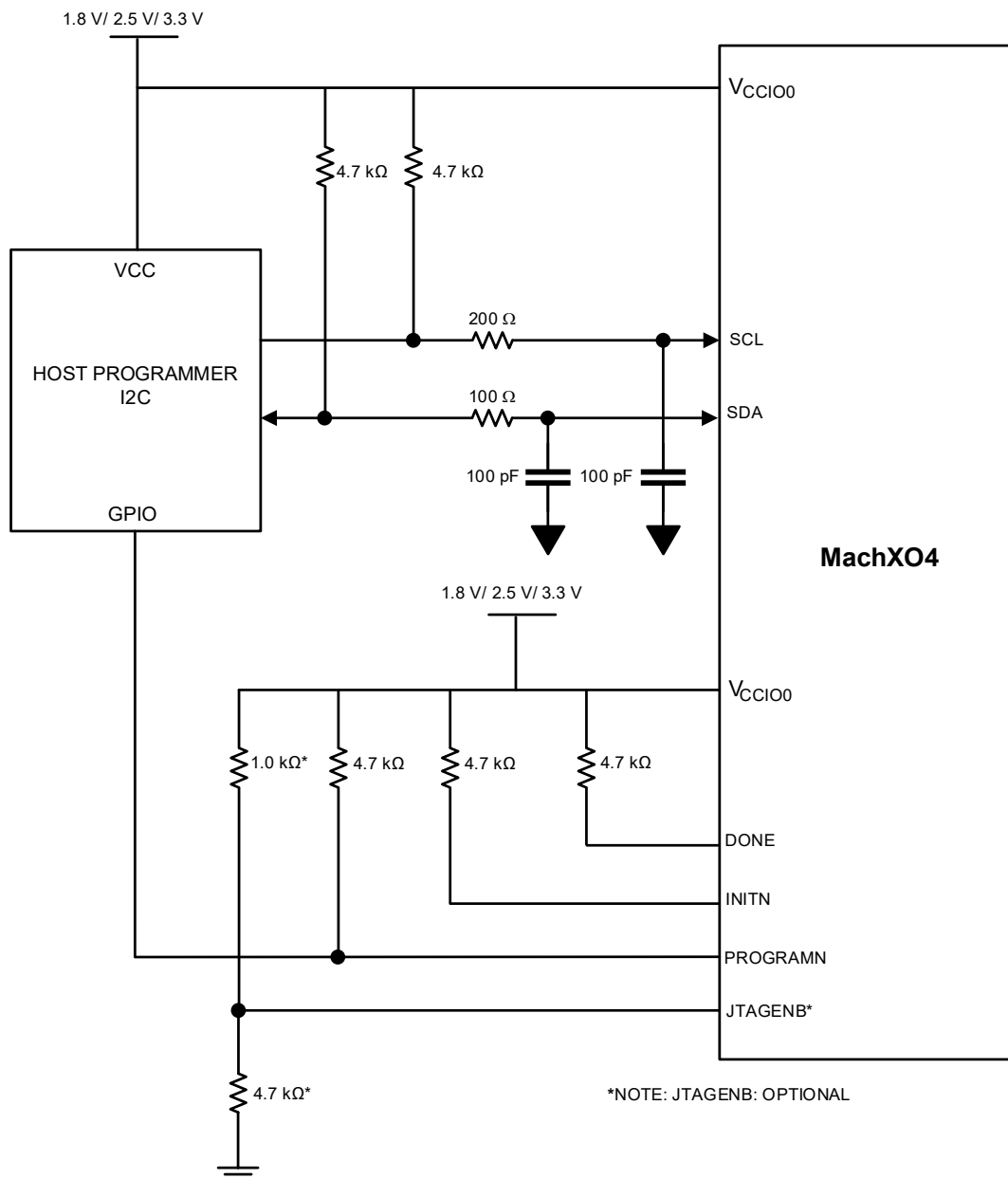
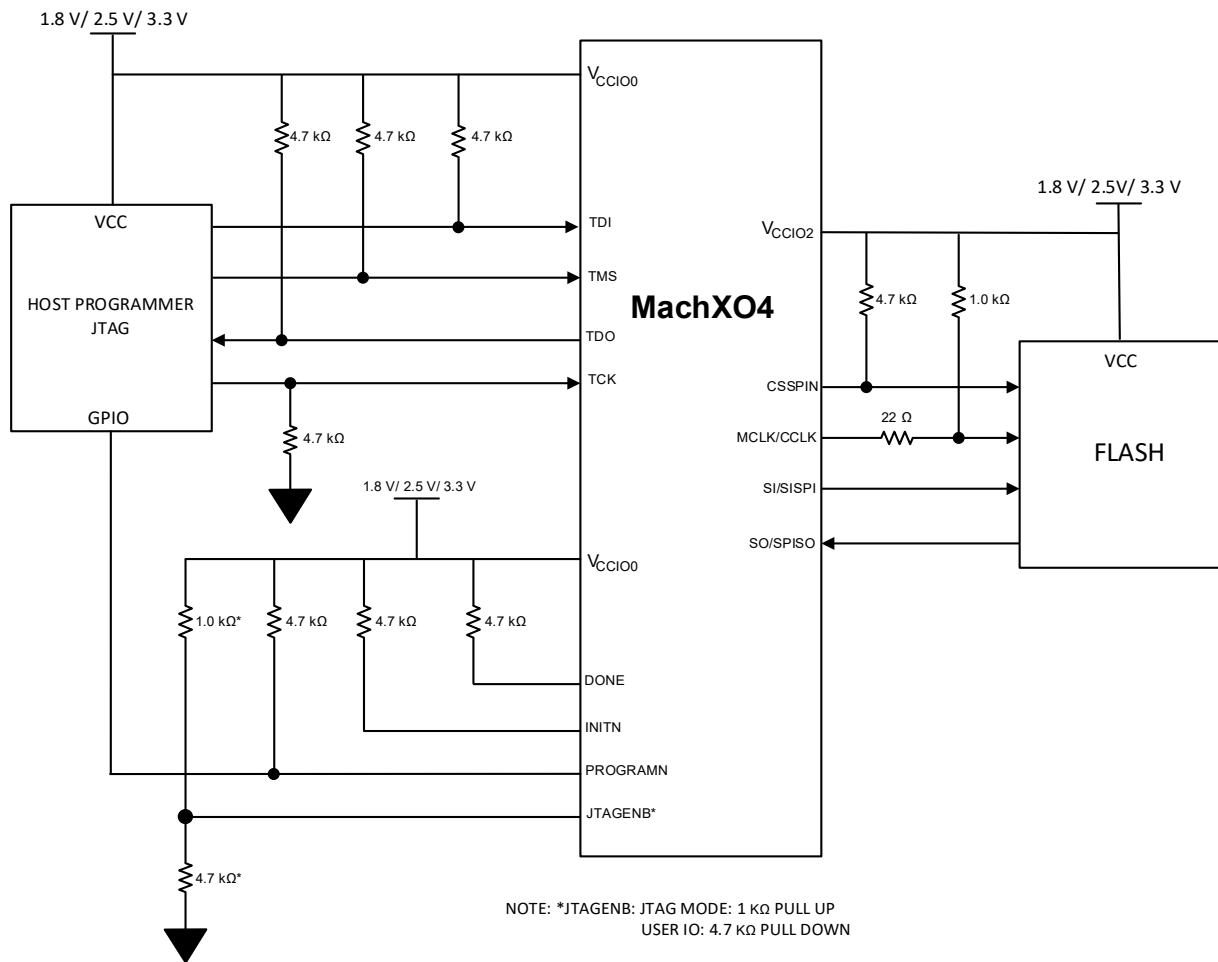


Figure 6.3. Typical Connections for Programming SRAM or Internal Flash via I2C





**Figure 6.4. Typical Connections for Programming External Flash via JTAG**

## 7. Controller SPI (MSPI)

When configuring from an external SPI Flash:

- The SPI Flash VCC and the MachXO4 device V<sub>CCIO2</sub> must be at the same voltage level.
- Ensure the SPI Flash V<sub>CC</sub> is within its recommended operating range. The SPI Flash should be supported in Lattice Radiant Programmer. To view the list of supported devices, open Lattice Radiant Programmer, select the **Help** menu, then search for **SPI Flash support**.
- For SPI Flash devices not listed under **SPI Flash Support**, the custom flash option may enable compatibility with unsupported devices.

## 8. PROGRAMN Initial Power Considerations

The MachXO4 PROGRAMN pin may be used as a general-purpose I/O in user run mode; however, it is recommended to use other GPIOs instead of PROGRAMN and JTAG pins for general-purpose I/O. The PROGRAMN pin becomes a general-purpose I/O only after the configuration bitstream is loaded. When power is applied to the MachXO4 device, the PROGRAMN input initially functions as PROGRAMN. It is critical that any signal input to the PROGRAMN exhibit high-to-low transition period longer than the time from  $V_{CC}$  (minimum) to INITN rising edge. Transitions faster than this period may prevent the MachXO4 from becoming operational. Refer to the description of PROGRAMN in the [MachXO4 Programming and Configuration User Guide \(FPGA-TN-02393\)](#).

## 9. Pinout Considerations

The MachXO4 device support many applications with high-speed interfaces. These include various rule-based pinouts that must be understood before implementating the PCB design. Pinout selection should be based on a clear understanding of the FPGA fabric's interface building blocks, including IOLOGIC blocks such as DDR, clock resource connectivity, and PLL usage. Refer to [Implementing High-Speed Interfaces with MachXO4 Devices \(FPGA-TN-02410\)](#) for rules pertaining to these interface types.

### 9.1. Differential Pair Pin Connections

Differential pairs must use pin name pairs ending in either A and B or C and D. The positive side of a differential pair must connect to pins ending in A or C, and the negative side must connect to pins ending in B or D.

#### Examples

- PT23A      DIFF\_SIGNAL1+
- PT23B      DIFF\_SIGNAL1-
- PT23C      DIFF\_SIGNAL2+
- PT23D      DIFF\_SIGNAL2-

## 10. sysI/O

The MachXO4 device provides flexibility to configure each I/O according to user requirements. These pins can be configured as input, output, or tri-state. Additionally, attributes such as PULLMODE, CLAMP, HYSTERESIS, VREF, OPENDRAIN, SLEWRATE, DIFFRESISTOR, TERMINATION, and DRIVE STRENGTH can be set. Refer to the [MachXO4 sysI/O User Guide \(FPGA-TN-02398\)](#) for more information.

For PULLMODE, pull-up and pull-down resistors can be configured. These resistors operate using a constant current with the following values:

**Table 10.1. Weak Pull-up/Pull-down Current Specifications**

	Parameter	Condition	Min	Max	Unit
Pull-up	I/O weak pull-up resistor current	$0 \leq V_{IN} \leq 0.7 \times V_{CCIO}$	-26	-309	$\mu A$
Pull-down	I/O weak pull-down resistor current	$V_{IL} (\text{max}) \leq V_{IN} \leq V_{CCIO}$	30	305	$\mu A$

## 11. True-LVDS Output Pin Assignments

True-LVDS outputs are located on the top bank (Bank 0) of the MachXO4-1300 and higher-density devices. When using LVDS outputs, connect a 2.5 V or 3.3 V supply to the Bank 0  $V_{CCIO}$  supply rails. Refer to the [MachXO4 sysIO User Guide \(FPGA-TN-02398\)](#) for more information on this.

## 12. PCI Clamp Pin Assignment

PCI clamps are available on the bottom I/O bank (Bank 2) of the MachXO4-1300 and higher-density devices. When PCI clamps are required by the system design, assign these pins to I/O Bank 2. For the clamp characteristic, refer to the IBIS buffer models on the Lattice website or in the Lattice Radiant design software.

## 13. Clock Inputs

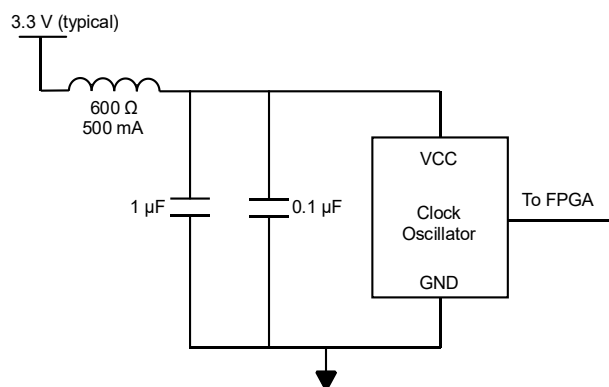
The MachXO4 device provides certain pins for use as clock inputs in each I/O bank. These pins are shared and can alternately be used for general purpose I/O.

When these pins are used for clocking purposes, you need to pay attention to minimize signal noise on these pins.

These shared clock input pins, typically named GPLL and PCLK, can be found under the Dual Function column of the pin-list .csv file. High-speed differential interfaces (such as MIPI) received by the FPGA must route their differential clock pair into a pair of inputs that support differential clocking, labeled PCLKTx\_y (+true) and PCLKCx\_y (-complement).

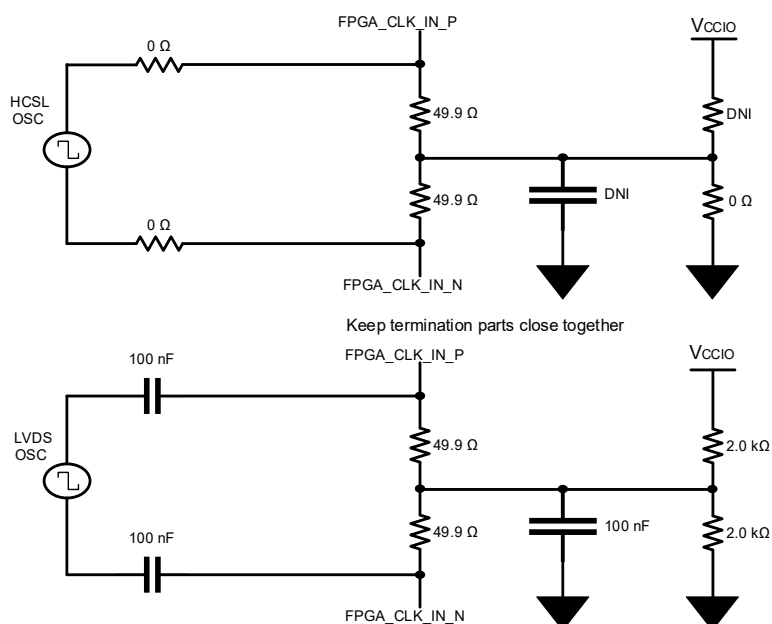
**Note:** For single-ended I/Os, use only PCLKT pins as primary CLK pads.

When providing an external reference clock to the FPGA, ensure that the oscillator's output voltage to the FPGA does not exceed the bank's voltage. Good power supply decoupling of the clock oscillator is required to reduce clock jitter. A typical bypassing circuit is shown in [Figure 13.1](#).



**Figure 13.1. Clock Oscillator Bypassing**

For differential clock inputs to banks with a  $V_{CCIO}$  voltage of 1.5 V or lower, it is recommended to use an HCSL oscillator to keep the clock voltage less than or equal to the bank's  $V_{CCIO}$ . An LVDS oscillator can also be used if AC is coupled and then DC is biased at half the  $V_{CCIO}$  voltage. Example dual footprint design supporting HCSL and LVDS is shown below in [Figure 13.2](#).



**Figure 13.2. PCB Dual Footprint Supporting HCSL and LVDS Oscillators**



## 13.1. PLL Reference Clock Locking

Reference clocks for PLLs must be stable before the PLL comes out of reset to guarantee proper PLL locking. PLLs should be held in reset using the PLL block's RST signal until the PLL's REFCLK signal is stable. See the [Checklist](#) section. The PLL reset procedure is usually required when an external oscillator or clock source becomes enabled or stable after the FPGA exits Power-On-Reset (POR). An example of a clock oscillator with a controlled enable pin is shown in [Figure 13.3](#).

**Note:** External board oscillators typically require 5 to 10 ms for their outputs to stabilize after being enabled. Check the oscillator's data sheet for the exact number.

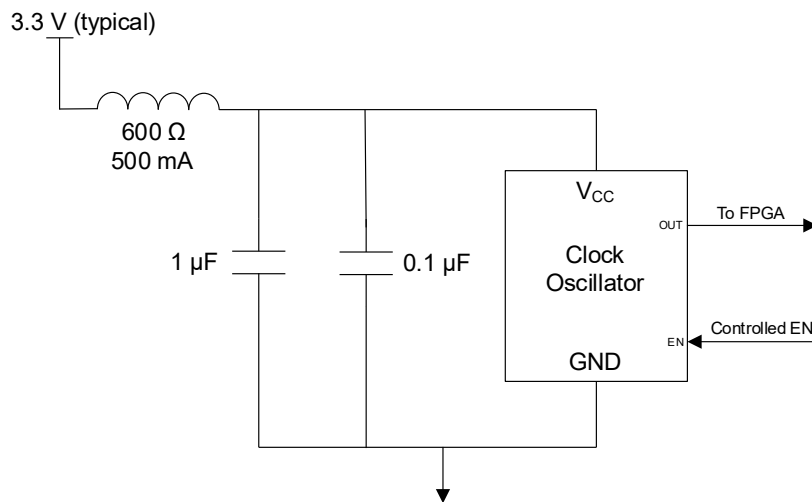


Figure 13.3. Clock Oscillator with Controlled Enable Pin

## 14. Issue: GPIO Input(s) Prevents Powering Down the FPGA

For HC devices where the design involves  $V_{CC}$  and bank  $V_{CCIOx}$  voltages that are the same (3.3 V or 2.5 V) and connected together, careful design consideration must be followed to avoid the FPGA not powering down fully and left operating in an undefined state.

Note: Chip failures can occur when the datasheet input current limits are exceeded.

### 14.1. GPIO Input Current Leakage Pathway

The FPGA is powered on, and the bit-stream program input CLAMPS ON.

While the FPGA powers down, the external circuit continues to drive input pins.

As the FPGA  $V_{CC}$  and  $V_{CCIOx}$  voltages drop, the GPIO input pins allow external devices to drive reverse current into the FPGA via the on-CLAMPS, and this current appears at the  $V_{CCIOx}$  pins, which are connected to  $V_{CC}$ , keeping the  $V_{CC}$  voltage high enough for the input CLAMPS to remain active.

Other devices, besides the FPGA, can be connected to the  $V_{CC}$  rail, with each device drawing current from the FPGA. As a result, the FPGA can pass enough reverse current to cause internal burnouts or failures to occur quickly or gradually, depending on the overcurrent of each pin and the number of pins involved.

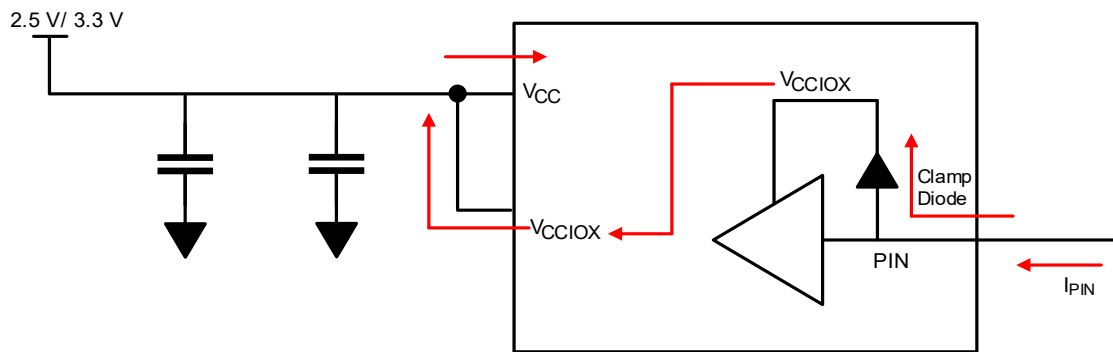


Figure 14.1. Potential Current Path for Powered Down FPGA with Driven Input

### 14.2. Workarounds

#### Workaround 1

- Turn off any external devices connected to the FPGA that are operating  $\geq 2.5$  V at the same time as the FPGA.

#### Workaround 2

- Configure software to keep GPIO CLAMPS OFF in the bitstream when CLAMPS are not required.

#### Workaround 3

- Ensure that external circuits do not exceed the datasheet I/O pad current limits for banks operating at  $\geq 2.5$  V.
- In each bank, the current should not exceed  $n \times 8$  mA. Where  $n$  represents the number of I/O pads in between two consecutive power pins. Please see below scenarios.
  - $V_{CCIO} - I/O_1 - I/O_2 - I/O_x - V_{CCIO}$
  - $GND - I/O_1 - I/O_2 - I/O_x - GND$
  - $V_{CCIO} - I/O_1 - I/O_2 - I/O_x - GND$

The I/O groupings can be found in the pin tables generated by the Lattice Radiant software.

Example: Limit the pin current by connecting a series resistor to an FPGA GPIO input.

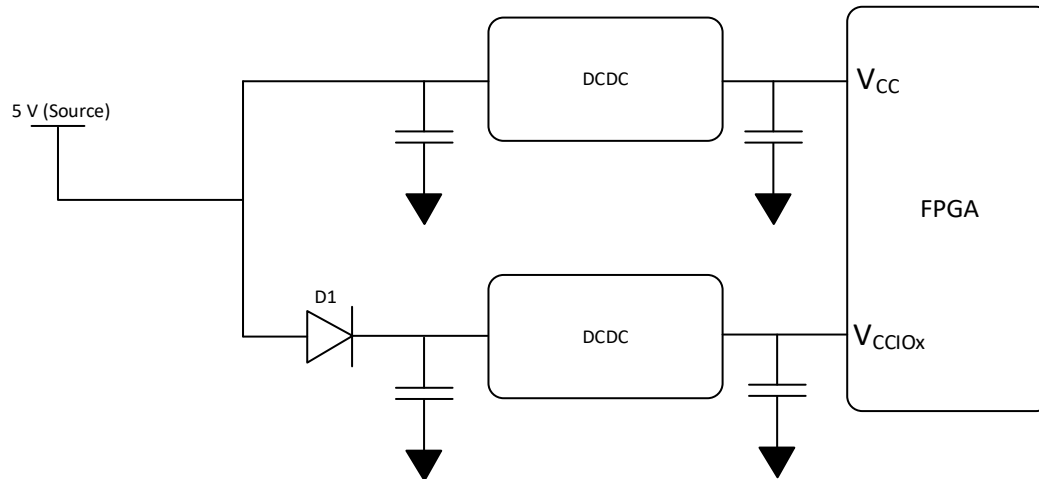
Most non-high-speed designs work well with a 200  $\Omega$  to 1 k $\Omega$  series resistor.

$$\text{Math: } R \times C \times 2.3 \text{ Tau} = \text{Trise} / \text{Tfall}$$

$$200 \Omega \text{ series resistor at GPIO input} \times 10 \text{ pF etch and pin capacitance} \times 2.3 \text{ Tau} = 4.6 \text{ ns Trise} / \text{Tfall}$$

#### Workaround 4

- For  $V_{CCIO}$ , use a separate voltage regulator with a diode (D1) connecting the voltage source to the input.



## 15. Layout Recommendations

A good design from a schematic should also reflect a good layout for the system design to work without any issues with noise or power distribution. Below are some of the recommended layouts in general.

1. All power should come from power planes. This is to ensure good power delivery and thermal stability.
2. Each power pin has its own decoupling capacitor, typically 100 nF, that should be placed as close as possible to each other.
3. The placement of analog circuits must be away from digital circuits or high switching components.
4. High-speed signals should have a clearance of five times the trace width of other signals.
5. High-speed signals that transition from one layer to another should have a corresponding transition ground if both reference planes are grounded. If the reference on the other layer is a  $V_{CC}$  plane, then a stitching capacitor should be used (ground to  $V_{CC}$ ).

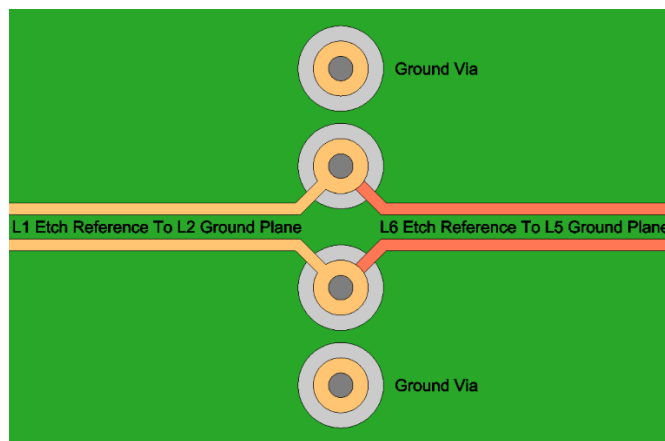


Figure 15.1. Ground Vias Implementation

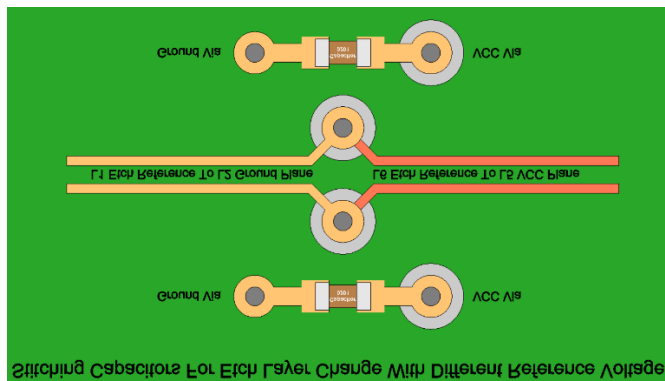


Figure 15.2. Stitching Vias Implementation

6. High-speed signals have a corresponding impedance requirement; calculate the necessary trace width and trace gap (differential gap) according to the desired stack-up. Verify trace dimensions with the PCB vendor.
7. For differential pairs, be sure to match the length as closely as possible. A good rule of thumb is to match up to  $\pm 5$  mils.

For further information on layout recommendations, refer to:

- [PCB Layout Recommendations for BGA Packages \(FPGA-TN-02024\)](#)
- [PCB Layout Recommendations for Leaded Packages \(FPGA-TN-02160\)](#)

## 16. Simulation and Board Measurement of Critical Signals

To ensure a design is reliable and will have high manufacturing yield, critical signals should be simulated during the design phase and then measured on the PCB assembly to verify proper function.

### 16.1. Critical Signals

Signals sensitive to Signal Integrity (SI) degradation are considered critical signals which require extra design and verification attention.

Typical critical signals include:

- Differential Pairs (LVDS, MIPI, and the like)
- Clocks (Oscillator Inputs, Output Clocks)
- Data with embedded clocks
- Interrupts (Edge Triggered)
- Logic signals travelling long distances requiring termination

### 16.2. Simulation

Lattice Semiconductor supplies an IBIS (I/O Buffer Information Specification) file to be used with simulation tools.

Popular simulations tools include:

- HyperLynx
- Sigridity
- SpectraQuest
- Micro-Cap (Free)

Most SI simulation tools are expensive and often have reoccurring subscription pricing. The expensive tools can import board design files and can easily supply accurate simulations which include crosstalk and other SI degrading effects.

Free IBIS tools (ex. Micro-cap) can supply useful basic simulations, but take extra effort to set up SI effects for multiple signals with different transmission line lengths, lossy transmission lines, and crosstalk.

Simulation results should be used to optimize each critical signal for best signal integrity:

- Define output pin drive strength.
- Define output pin slew rate.
- Define output pin termination design (ex. output series termination resistor value).
- Define setting of internal pin pull-up and pull-down resistors.
- Improve PCB layout.

### 16.3. Board Measurements

Critical signals should be measured on the actual PCB assembly using an Oscilloscope. Verify proper signaling function and signal integrity (that is, eye diagram, SI parameters).

Measurement results should be used to optimize each critical signal for best signal integrity:

- Adjust output pin drive strength.
- Adjust output pin slew rate.
- Adjust output pin termination design (ex. output series termination resistor value).
- Adjust the setting of internal pin pull-up and pull-down resistors.

Specification compliance testing is recommended for popular signaling methods (ex. USB, MIPI).

## 17. SSO (Simultaneous Switching Output) Design Check

Users should verify designs that will not have functional failures due to SSO voltage drops (sometimes call SSO Noise, Ground Bounce, or Power Bounce).

SSO voltage drops are mainly caused by package inductance combined with dynamic switching current causing  $Ldi/dt$  voltage drops.

The Lattice SSO Tool should be used to provide SSO voltage drop estimates.

### 17.1. SSO Failures – Each of the following can lead to SSO failures

1. Many simultaneous switching outputs in the same I/O bank.  
The more simultaneous switching outputs in a bank the greater the 'di' current, and thus greater  $Ldi/dt$  voltage drops.
2. I/Os slew rates set to FAST (and sometimes MEDIUM).  
Faster slew rates reduce the 'dt' time, and thus increase the  $Ldi/dt$  voltage drops.
3. I/Os output current set high (ex. 8mA – 16mA).  
The greater the I/O output current the greater the 'di' current, and thus greater  $Ldi/dt$  voltage drops.
4. I/Os capacitive loading is relatively high (especially  $> 15pF$ )  
High capacitance loading increases the 'di' current, and thus increases  $Ldi/dt$  voltage drops.
5. I/O Banks with low voltage rails (ex. LVCMOS 1.0V – LVCMOS 1.5V) have small voltage margins and are more susceptible to  $Ldi/dt$  ground & power violations.

### 17.2. SSO Mitigations

1. Split up simultaneous switching outputs into multiple banks (where timing permits.)  
The fewer simultaneous switching outputs in a bank the lower the 'di' current, and thus lower  $Ldi/dt$  voltage drops.
2. Reduce I/O slew rates to MEDIUM or even better SLOW if timing allows.  
The increase in slew time increases 'dt' and thus reduces  $Ldi/dt$  voltage drops.
3. Reduce I/Os output current (ex. 4mA), where timing and signal quality permit.  
Reducing the I/O output current reduces 'di' current, and thus reduces  $Ldi/dt$  voltage drops.
4. Reduce I/Os capacitive loading (this usually requires PCB design changes).  
Reducing capacitive loading reduces 'di' current, and thus reduces  $Ldi/dt$  voltage drops.
5. Increase I/O Bank voltage rails (this often requires PCB design changes). When above mitigations do not provide enough design margin, then increasing I/O Bank voltage can increase absolute voltage margins and provide enough design margin for reliable operation.

## 18. Checklist

**Table 18.1. Hardware Checklist**

	MachXO4 Hardware Checklist Item	OK	N/A
<b>1</b>	<b>Power Supply</b>		
1.1	Core Supply VCC at 1.2 V for E device		
1.2	Core Supply VCC at 2.5 V or 3.3 V for C device		
1.3	I/O power supply VCCIO[0-5] at 1.2 V to 3.3 V		
1.4	Power Estimation		
1.5	Follow the recommended power filtering groups and components in <a href="#">Table 3.1. Recommended Power Filtering Groups and Components</a> .		
1.6	All ground pins need to be connected to the board's ground plane.		
1.7	Bank I/O supplies.		
1.8	Connect the unused V <sub>CCIOx</sub> to a power rail. Do not leave it open.		
1.9	All configurations of V <sub>CCIO</sub> (Banks 0,2), when used with the configuration interfaces (example: SPI Flash Memory Devices), need to match the voltage specifications.		
<b>2</b>	<b>Configuration</b>		
2.1	Configuration options		
2.2	Apply pull-up resistor on PROGRAMN, INITN, and DONE as described in <a href="#">Section 6 Configuration Considerations</a> .		
2.3	Pull-up on SPI mode pins, per <a href="#">Section 6 Configuration Considerations</a> .		
2.4	Pull-up on I2C mode pins, per <a href="#">Section 6 Configuration Considerations</a> .		
2.5	Ensure the JTAG_EN pin remains accessible on the PCB to allow JTAG port recovery, particularly during development.		
2.6	Apply a pull-up or pull-down resistor to the JTAG_EN pin.		
2.7	Apply pull-down resistor to JTAG TCK as specified in <a href="#">Section 6 Configuration Considerations</a> .		
2.8	Pull-up on TMS, TDI, and TDO.		
2.9	PROGRAMN high-to-low transition time period is larger than the V <sub>CC</sub> (min) to INITN rising edge time period.		
2.10	The Controller SPI (MSPI) voltage should match V <sub>CCIO2</sub> voltage.		
<b>3</b>	<b>I2C Filter</b>		
3.1	RC filter for I2C bus, per <a href="#">Table 6.1. Default States of the sysCONFIG Pins1</a> .		
<b>4</b>	<b>I/O pin assignment</b>		
4.1	Differential pairs must use pin name pairs ending in A and B or C and D. The positive side of a differential pairs — connect to pins ending in A or C. The negative side of a differential pair — connect to pins ending in B or D.		
4.2	True LVDS output pin assignments use Bank 0 with V <sub>CCIO0</sub> connected to a 2.5 V or 3.3 V supply.		
4.3	PCI clamp requirement considerations.		
4.4	Connect single-ended clock inputs to the FPGA using the PCLKTx_y pins, which support low skew routing throughout the FPGA fabric.		
4.5	Connect differential clock inputs to the FPGA using the PCLKTx_y and PCLKCx_y pins, which support low skew routing throughout the FPGA fabric.		
<b>5</b>	<b>Miscellaneous</b>		
5.1	Verify that no GPIO clamp issues exist, as described in <a href="#">Section 14 Issue: GPIO Input(s) Prevents Powering Down the FPGA</a> .		
5.2	Run SSO tool as required per section <a href="#">SSO (Simultaneous Switching Output) Design Check</a> .		
5.3	Run simulations per section <a href="#">Simulation and Board Measurement of Critical Signals</a> .		

## References

- [MachXO4](#) web page
- [MachXO4 Family Data Sheet \(FPGA-DS-02125\)](#)
- [MachXO4 Programming and Configuration User Guide \(FPGA-TN-02393\)](#)
- [MachXO4 sysIO User Guide \(FPGA-TN-02398\)](#)
- [Implementing High-Speed Interfaces with MachXO4 Devices \(FPGA-TN-02410\)](#)
- [Using Hardened Control Functions in MachXO4 Devices \(FPGA-TN-02403\)](#)
- [Power and Thermal Estimation and Management for MachXO4 Devices \(FPGA-TN-02409\)](#)
- [PCB Layout Recommendations for BGA Packages \(FPGA-TN-02024\)](#)
- [PCB Layout Recommendations for Leaded Packages \(FPGA-TN-02160\)](#)
- [Lattice Radiant](#) FPGA design software
- [Lattice Insights](#) for Lattice Semiconductor training courses and learning plans



## Technical Support Assistance

Submit a technical support case through [www.latticesemi.com/techsupport](http://www.latticesemi.com/techsupport).

For frequently asked questions, refer to the Lattice Answer Database at <https://www.latticesemi.com/Support/AnswerDatabase>.

## Revision History

### Revision 1.0, December 2025

Section	Change Summary
All	Initial release



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